

**Search Notes**

Application/Control No.

10/501,917

Examiner

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Applicant(s)/Patent under  
Reexamination

KATSUNUMA, TAKAYUKI

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	711	10/25/2006	BT
438	713	10/25/2006	BT
438	728	10/25/2006	BT
438	743	10/25/2006	BT

**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	10/25/2006	BT
438/706 text search only	10/25/2006	BT